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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/753,075	01/08/2004	Holger Hoppe	543822003100	5426
25227	7590	11/01/2006	EXAMINER	
MORRISON & FOERSTER LLP 1650 TYSONS BOULEVARD SUITE 300 MCLEAN, VA 22102			ABRAMS, NEIL	
			ART UNIT	PAPER NUMBER
			2839	

DATE MAILED: 11/01/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No. 10/753,075	Applicant(s) HOPPE, HOLGER	
	Examiner Neil Abrams	Art Unit 2839	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 10-10-06 Request for continued examination
 2a) ☐ This action is FINAL. 2b) ☒ This action is non-final.
 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-15 is/are pending in the application.
 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
 5) ☐ Claim(s) _____ is/are allowed.
 6) ☒ Claim(s) 1-15 is/are rejected.
 7) ☐ Claim(s) _____ is/are objected to.
 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
 Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
 Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 a) ☐ All b) ☐ Some * c) ☐ None of:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
 * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | Paper No(s)/Mail Date. _____ |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO/SB/08) | 5) <input type="checkbox"/> Notice of Informal Patent Application |
| Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

The filling of a Request for Continued Examination on October 10, 2006 is acknowledged. All amendments have been entered. A first office action follows.

1. Claims 1-10, 14-15 are rejected under 35 U.S.C. 102(b) as anticipated by or, in the alternative, under 35 U.S.C. 103(a) as obvious over Grabbe 369 alone or taken in view of Volz and Isaac.

1. Grabbe socket 20, figures 5-7 is receive component 2 and includes pins 40 which include portions 50, 51 that extend from the housing floor 28 and are bent back upward at 56, are connected to device, pcb14 by solderless surface mounting and that are arranged at an angle of 30 degrees with respect to x-axis. For claims 1-10, 14, all features appear by Grabbe since test, burn-in, aspect is functional and defines no structure over Grabbe and since semiconductor not positively recited. Should the testing aspect be at issue and for method claim 15 note that Grabbe does not disclose testing use. Isasc and Volz use sockets for testing. Obvious to therefore use Grabbe socket for semiconductor testing and this would only be a standard use for such sockets. Such use covers the claim 15 method steps. Other aspects, should issues arise deemed obvious variations.

2. Claims 11-13 are rejected under 35 U.S.C. 103(a) as being unpatentable over the references as applied to claim 1 above, and further in view of Grabbe 826.

3. Grabbe 369 includes fasteners, clamps at 12 but their use is not clear. Grabbe 826 uses fasteners at 20. Isasc uses these at 46. Obvious to add same to Grabbe 360 to secure the socket to the pcb.

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4. Claims 1-10 and 14-15 are rejected under 35 U.S.C. 102(b) as anticipated by or, in the alternative, under 35 U.S.C. 103(a) as obvious over McHugh alone or taken in view of Isaac, Volz and Grabbe 369.

5. McHugh, figure 6, socket includes pins 5 that are to engage component 7 and that extend below socket surface at 533 and that turns upward, that engages device 9 be solderless surface mounting and are oriented at an angle of about 45 degrees, figure

3. All claims 1-10, 14 features taught by McHugh since test aspect provides no structure over McHugh. For claim 5, obvious to use copper as that is standard contact material.

6. As alternative for claims 1-10, 14 and claim 15, McHugh does not disclose testing steps, however Volz and Isaac use test steps. Obvious to so use the McHugh socket as that would be a standard use for such sockets. While McHugh, figures 3, 8, 9, clearly shows angled contact orientation the feature is not discussed. Grabbe added for discussion of 30 degrees orientation feature. Should issue arise, also obvious to so orient McHugh contacts as taught by Grabbe for a more dense spacing.

7. McHugh, figure 10 also applied and shows socket with contacts 10 having upward bend portion 20 but do not show angled orientation. Grabbe shows contacts with angled orientation. Obvious to so arrange the McHugh figure 10 contacts for a more dense spacing. Volz and Isaac applied as above.

8. Claims 11-13 rejected under 35 U.S.C. 103(a) as being unpatentable over McHugh, etc as applied to claim 1 above, and further in view of Grabbe 826.

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9. McHugh lacks a device (screw) for pressing the pin against the device (pcb) 9. Isaac at 46 and Grabbe 826 at 20 use such clamping screws. Obvious to use same in McHugh to secure the socket to the pcb.
10. Applicant's arguments filed with the amendment have been fully considered but they are not persuasive.
11. Grabbe 369 and McHugh even as shown are usable as testing sockets for semiconductor, see McHugh, figure 1. Volz and Isaac are not essential and are used only to provide clear teaching of use of sockets for testing. Applicant, who shown a socket at 12a with no test features cannot properly assert Grabbe and McHugh are not test sockets.
12. As to the "arranged obliquely" feature, arguments presented are unclear. The feature, as disclosed, refers to applicants figure 3 arrangement, not to the angles of contact upward bending as may be seen in figure 2 and 5A; only figure 3 is a "bottom view".

Any inquiry concerning this communication should be directed to Neil Abrams at telephone number 571-272-2089


NEIL ABRAMS
PRIMARY EXAMINER